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NO. 1877—P. 7

*Not Supplied**original stamp date 12/10/99*

Submitted with IDS of December 7, 1999

Sheet 1 of 1

Form PTO-1449  
(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Attorney Docket No. 0756-945

Serial No. 08/169,127

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Applicant: Hisato SHINOHARA et al.

Filing Date: December 20, 1993

Group: 1762

**U.S. PATENT DOCUMENTS**

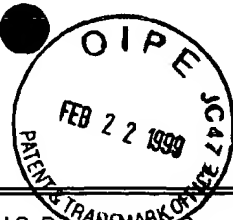
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>Prop</i>	60-52390	03/25/85	Japan			Full	
<i>Prop</i>	60-260393	12/23/85	Japan			Full	
	61-31288	02/13/86	Japan			Full	
<i>Prop</i>	62-143847	06/27/87	Japan			Full	
<i>Prop</i>	2-222154	09/04/90	Japan			Full	
	DE 39 25 085 C1	01/10/91	Germany			Full	
	61-72549	04/14/86	Japan			Full	

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)Examiner *[Signature]*Date Considered *4/19/04*

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Submitted with IDS of February 19, 1999

attach to #34

Sheet 1 of 1

Form PTO-1449  
(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Attorney Docket No. 0756-945

Serial No. 08/169,127

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Hisato SHINOHARA et al.

Filing Date: December 20, 1993

Group: TTT2/762

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>[initials]</i>	RE 33,947	06/02/92	Shinohara			
<i>[initials]</i>	4,059,461	11/22/77	Fan et al			
<i>[initials]</i>	4,233,626	11/11/80	Bell			
<i>[initials]</i>	4,270,132	05/26/81	Bell			
<i>[initials]</i>	4,309,225	01/05/82	Fan et al			
<i>[initials]</i>	4,314,256	02/02/82	Petrov et al			
<i>[initials]</i>	4,568,409	02/04/86	Caplan			
<i>[initials]</i>	4,861,964	08/29/89	Shinohara			
<i>[initials]</i>	5,708,252	01/13/98	Shinohara et al			

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation Yes No
53-122403 <i>* Same</i>	10/25/78	Japan	US PN 4,233,626	above	Abstract
60-052390	03/25/85	Japan	Vici et al		+ Full Trans Abstract
60-224282 (Japanese & English)	11/08/85	Japan	Yamaguchi		X
60-227484 (Japanese & English)	11/12/85	Japan	Yamaguchi		X
60-260393	12/23/85	Japan	Yamaguchi		+ Full Trans Abstract
61-031288	02/13/86	Japan	Mizuhara		Abstract
62-143847	06/27/87	Japan	Yamamoto et al		+ Full Trans Abstract
63-084789	04/15/88	Japan	US PN 4,861,964 & 5,708,252	above	Abstract
2-222154	09/04/90	Japan	Shinohara et al		+ Full Trans Abstract
DE 28 12 868 A1	10/12/78	Germany	Bell	US PN 4,233,626	above Abstract

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>[initials]</i>	Gladstone et al., "Liquid Crystal Display Device Configuration", IBM Technical Disclosure Bulletin, Vol. 15, No. 2, July 1972, pp. 437-438
<i>[initials]</i>	Bahadur, "Molecular Crystals and Liquid Crystals", Vol. 109, No. 1, New York, (1984), pp. 24-26

Examiner

Date Considered

4/15/04

\*EXAMINER: Initial if citation considered, whether or not citation is in compliance with MPEP 609; Draw line through citation if not in compliance and not considered. Include copy of this form with next communication to applicant.

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PTO/SB/08A (10-01)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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Substitute for form 1449A/PTO		<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (use as many sheets as necessary)		Application Number	08/169,127
		Filing Date	December 20, 1993
		First Named Inventor	Hisato SHINOHARA et al.
		Art Unit	1762
		Examiner Name	Marianne L. Padgett
Sheet 1 of	Attorney Docket Number	740756-945	

U.S. PATENT DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)			
MPP		US-5,636,826	August 12, 1997	Misawa et al.	
		US-			
		US-			
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FOREIGN PATENT DOCUMENTS						
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	r <sup>3</sup>
		Country Code <sup>4</sup> Number <sup>5</sup> Kind Code <sup>6</sup> (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	r <sup>3</sup>

Examiner Signature	Date Considered
Marianne L. Padgett	1/12/02

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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

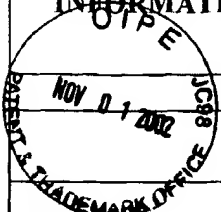
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Submitted with IDS of October 1, 2002

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Sheet 1 of 1

<b>Form PTO-1449</b> (Rev. 8-83)	<b>U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>	<b>Attorney Docket No.</b> 740756-945	<b>Serial No.</b> 08/169,127
<b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)		<b>Applicant:</b> Hisato SHINOHARA et al.	
		<b>Filing Date:</b> December 20, 1993	<b>Group:</b> 1762



**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>[Signature]</i>	U.S. Patent No. 5,432,122	7/11/1995	Chae			

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TC 1700

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>[Signature]</i>	63-195149	08/12/1988	Japan			Full	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

<i>[Signature]</i>	Mimura et al., "High-Performance Low-Temperature Poly-Si TFTs for LCD", IEDM 87, pp. 436-439, (January 1987).
<b>Examiner</b>	<b>Date Considered</b> 4/15/03

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Form PTO-1449  
(Rev. 8-83)

U.S. Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-0945

Serial No. 08/169,127

INFORMATION DISCLOSURE STATEMENT

SEP 09 2002

Applicants: Hisato SHINOHARA et al.

Filing Date: December 20, 1993

Gr up Art Unit: 1762

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>MP</i>	3,848,104	11/12/1974	Locke			
	3,877,777	04/15/1975	Glenn, Jr.			
	4,154,530	05/15/1979	Connolly, Jr. et al.			
	4,341,569	07/27/1982	Yaron et al.			
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	4,370,175	01/25/1983	Levatter			
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	5,432,112	07/11/1995	Hong			
	5,453,858	09/26/1995	Yamazaki			
	5,897,799	04/27/1999	Yamazaki et al.			
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<i>MP</i>	6,149,988	11/21/2000	Shinohara et al.			

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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>MP</i>	0 322 258	06/28/1989	EP	<i>Shinohara et al</i>		Full Eng	
	01-241862	09/26/1989	JP	<i>Samekuma et al</i>		Full Eng	
	04-338631	11/25/1992	JP	<i>Sato et al</i>		Full Eng	
	05-021339	01/29/1993	JP	<i>Hino et al</i>		Full Eng	
	55-032026	03/06/1980	JP	<i>Yamato et al</i>		Full Eng	
	57-079914	05/19/1982	JP	<i>Hayashi Hiroyuki</i>		Eng Abst only	X
	60-245124	12/04/1985	JP	<i>Settsuo Utsui</i>		Full Eng	
	60-257511	12/19/1985	JP	<i>Kano et al</i>		Full Eng	
<i>MP</i>	61-080815	04/24/1986	JP	<i>Settsuo Utsui</i>		Full Eng	

Examiner

Date Considered

4/15/04

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Form PTO-1449  
(Rev. 8-83)

U.S. Department of Commerce  
Patent and Trademark Office

Atty Docket 0756-0943

Serial N .08/169,127

INFORMATION DISCLOSURE STATEMENT

Applicants: Hisato SHINOHARA et al.

Filing Date: December 20, 1993

Group Art Unit: 1762

SEP 09 2002

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>MPP</i>	61-141174	06/28/1986	JP <i>Yamato</i>			Full Eng	
<i>MPP</i>	63-025933	02/03/1988	JP <i>Ishitani</i>			Full Eng	
	63-084789	04/15/1988	JP			Eng Abst	
<i>MPP</i>	63-195149	08/12/1988	JP <i>Mizutani et al</i>			Eng Abst Full	

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

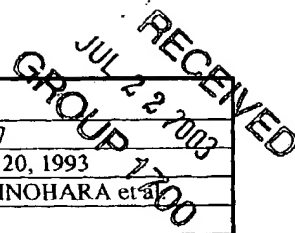
Examiner Initial	
<i>MPP</i>	Grimm, "Optical System for Laser Machining of Narrow Slots", pp. 2641-2642, February 1972, IBM Technical Disclosure Bulletin, Vol. 14, No. 9
<i>MPP</i>	Harvey pp. 10-11, January 1962, Optics: Experiments and Demonstration
<i>MPP</i>	"Excimer Laser Annealing Apparatus Leonix", pp. 196-197 (Translation pages 1-4), October 1992, Semiconductor World <i>except from chapter 2, not used, no author</i>
<i>MPP</i>	Kaneko, "Excimer Laser Annealed Poly-Crystalline Silicon TFT", pp. 679-683, January 1990, T. IEEE Japan, Vol. 110-A, No. 10 <i>translation only provided</i>
<i>MPP</i>	Morikawa et al., "Special Article: Present Situation of Laser Processing Technique", pp. 66-68, August 1990, Laser Group, Engineering Section, Mechatronics Apparatus Division, with Full English Translation
<i>MPP</i>	Misura et al., "High-Performance Low-Temperature Poly-Si TFT's for LCD", pp. 436-439, January 1987, IEDM-87
<i>MPP</i>	Fujii et al., "A 10MHz Integrated Driver Circuit for Active-Matrix LCDs Using Laser-Recrystallized Silicon TFTs", pp. 448-451, January 1987, IEDM 87
<i>MPP</i>	Sera et al., "High-Performance TFT's Fabricated by XeCl Excimer Laser Annealing of Hydrogenated Amorphous-Silicon Film", pp. 2868-2872, December 1989, IEEE Transactions on Electron Devices, Vol. 36, No. 12
<i>MPP</i>	Sameshima et al., "XeCl Excimer Laser Annealing Used to Fabricate Poly-Si TFT's", pp. 1789-1793, October 1989, Japanese Journal of Applied Physics, Vol. 28, No. 10
<i>MPP</i>	McGrath, "Applications of Excimer Lasers in Microelectronics", pp. 165-169, December 1983, Solid State Technology

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- document re-supplied  
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Date Considered *4/15/04*

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Substitute for form 1449A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	08/169,127
				Filing Date	December 20, 1993
				First Named Inventor	Hisato SHINOHARA et al.
				Art Unit	1762
				Examiner Name	Marianne Padgett
Sheet	1	of	1	Attorney Docket Number	740756-945

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		Number - Kind Code <sup>2</sup> (if known)			
		US-			
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FOREIGN PATENT DOCUMENTS						
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		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
		JP-51-104846	09/17/1976	HANDA		Concise Statement
		JP-52-121893	10/13/1977	SHIBATA et al.		AB
		JP-54-120498	09/19/1979	YAMAGUCHI et al.		AB

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>3</sup>

Examiner Signature		Date Considered	4/15/04
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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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